



USG10R024H

Power MOSFET

N-CHANNEL SGT ENHANCEMENT POWER MOSFET

■ DESCRIPTION

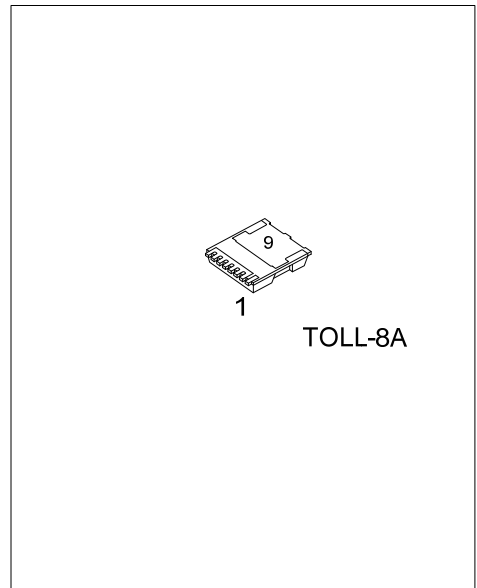
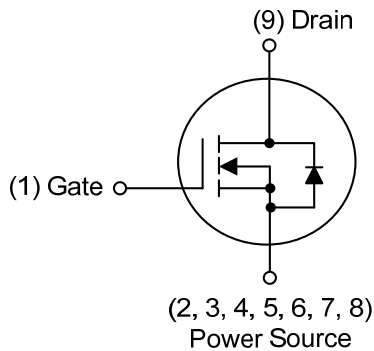
The UTC **USG10R024H** is a N-channel Power MOSFET, it uses UTC's advanced technology to provide the customers with high switching speed and low gate charge, etc.

The UTC **USG10R024H** applies to primary side switch, synchronous rectifier, Motor Drives, etc.

■ FEATURES

- * $R_{DS(ON)} \leq 2.4 \text{ m}\Omega @ V_{GS}=10V, I_D=80A$
- * High Cell Density Trench Technology
- * High Power and Current Handling Capability

■ SYMBOL



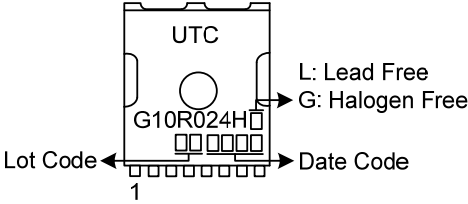
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment							Packing		
Lead Free	Halogen Free		1	2	3	4	5	6	7		8	9
USG10R024HL-T8A-R	USG10R024HG-T8A-R	TOLL-8A	G	S	S	S	S	S	S	S	D	Tape Reel

Note: Pin Assignment: G: Gate S: Source D: Drain

<p>USG10R024HG-T8A-R</p>	<p>(1) R: Tape Reel</p> <p>(2) T8A: TOLL-8A</p> <p>(3) G: Halogen Free and Lead Free, L: Lead Free</p>
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MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage	V_{DSS}	100	V
Gate-Source Voltage	V_{GSS}	± 20	V
Drain Current	Continuous	I_D	170
	Pulsed (Note 2)	I_{DM}	340
Single Pulsed Avalanche Energy (Note 3)	E_{AS}	76	mJ
Peak Diode Recovery dv/dt (Note 4)	dv/dt	3.5	V/ns
Power Dissipation	P_D	300	W
Junction Temperature	T_J	+150	$^\circ\text{C}$
Storage Temperature	T_{STG}	-55 ~ +150	$^\circ\text{C}$

- Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
 3. $L = 0.1\text{mH}$, $I_{AS} = 39.1\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
 4. $I_{SD} \leq 30\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, $T_J \leq T_{JMAX}$, $T_J = 25^\circ\text{C}$.

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	35	$^\circ\text{C}/\text{W}$
Junction to Case	θ_{JC}	0.42 (Note)	$^\circ\text{C}/\text{W}$

Note: Device mounted on FR-4 substrate P_c board, 2oz copper, with 1inch square copper plate.

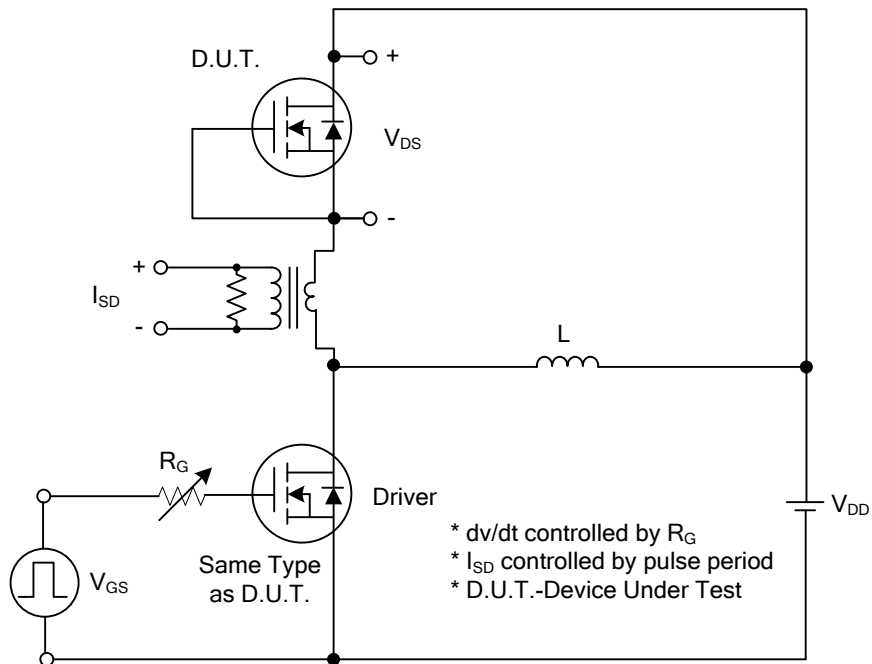
■ ELECTRICAL CHARACTERISTICS (T_J=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V	100			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =100V, V _{GS} =0V			1	μA
Gate-Source Leakage Current	Forward	V _{GS} =+20V, V _{DS} =0V			+100	nA
	Reverse	V _{GS} =-20V, V _{DS} =0V			-100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	2.0		4.0	V
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =80A			2.4	mΩ
DYNAMIC PARAMETERS						
Input Capacitance	C _{ISS}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz		7817		pF
Output Capacitance	C _{OSS}			3524		pF
Reverse Transfer Capacitance	C _{RSS}			456		pF
SWITCHING PARAMETERS						
Total Gate Charge	Q _G	V _{DS} =80V, V _{GS} =10V, I _D =170A		198		nC
Gate to Source Charge	Q _{GS}			44		nC
Gate to Drain Charge	Q _{GD}			73		nC
Turn-ON Delay Time	t _{D(ON)}	V _{DD} =50V, V _{GS} =10V, I _D =170A, R _G =3Ω		28		ns
Rise Time	t _R			33		ns
Turn-OFF Delay Time	t _{D(OFF)}			87		ns
Fall-Time	t _F			41		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Continuous Drain-Source Diode Forward Current	I _S				170	A
Maximum Pulsed Drain-Source Diode Forward Current	I _{SM}				340	A
Drain-Source Diode Forward Voltage	V _{SD}	I _F =170A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time	t _{rr}	I _S =30A, di/dt=100A/μs		288		ns
Body Diode Reverse Recovery Charge	Q _{rr}				769	

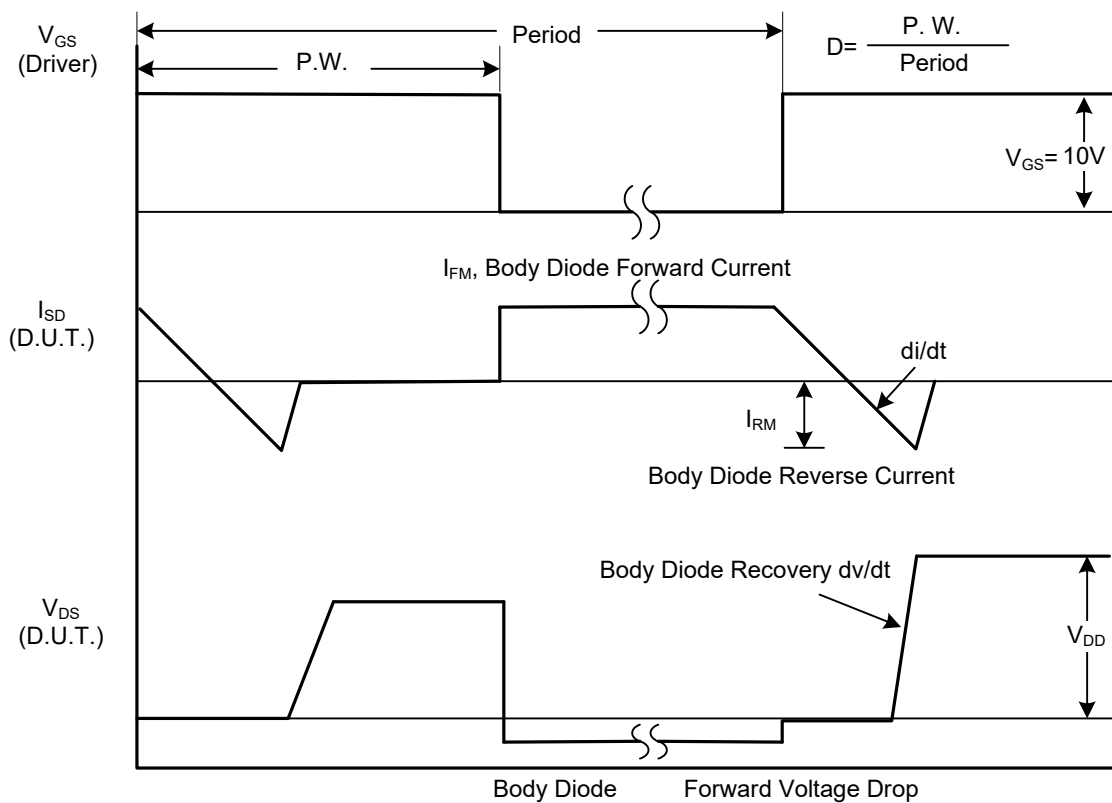
Notes: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%.

2. Essentially independent of operating temperature.

TEST CIRCUITS AND WAVEFORMS

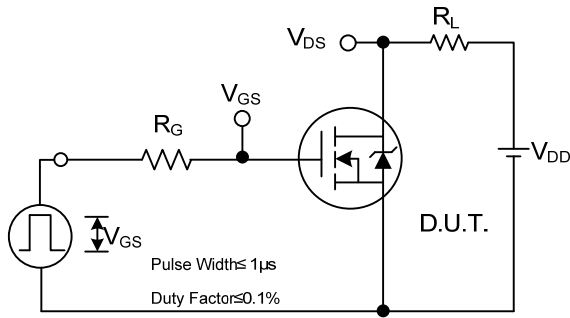


Peak Diode Recovery dv/dt Test Circuit

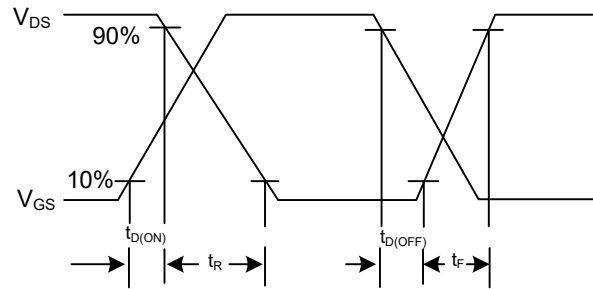


Peak Diode Recovery dv/dt Waveforms

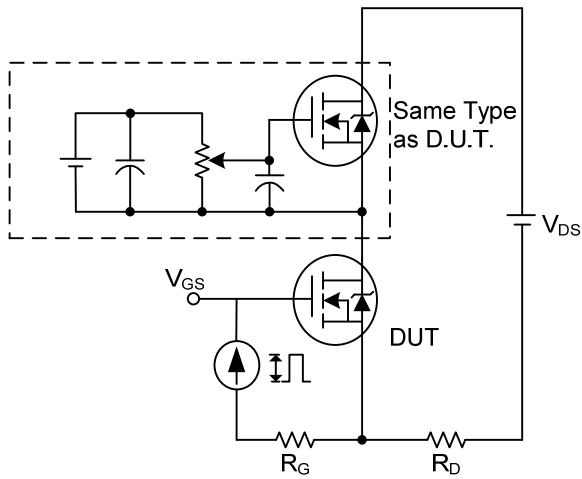
TEST CIRCUITS AND WAVEFORMS



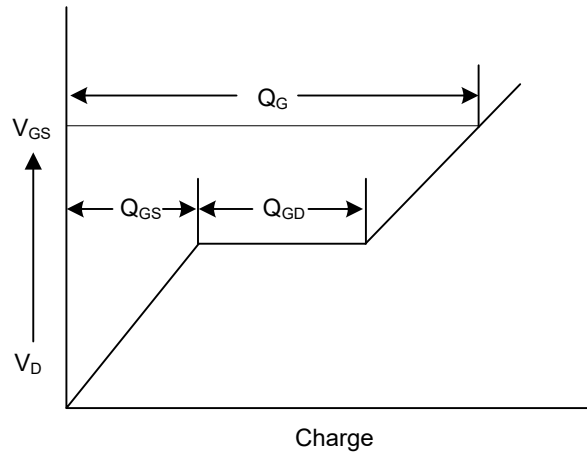
Switching Test Circuit



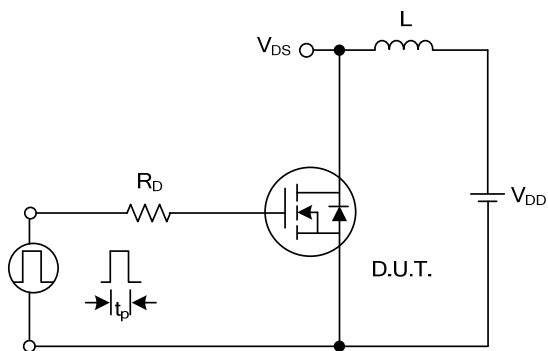
Switching Waveforms



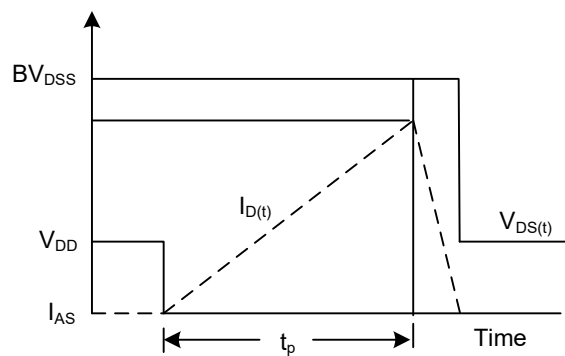
Gate Charge Test Circuit



Gate Charge Waveform

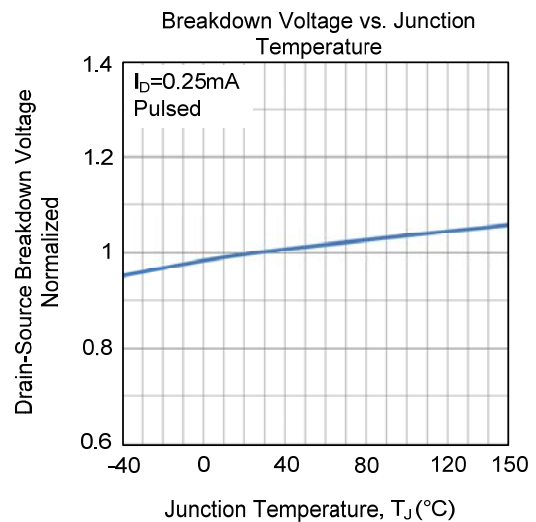
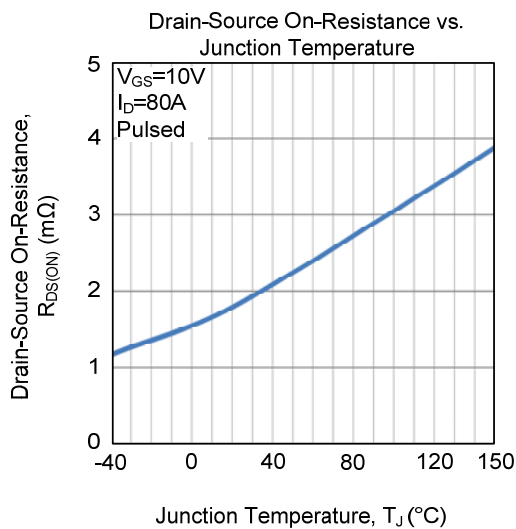
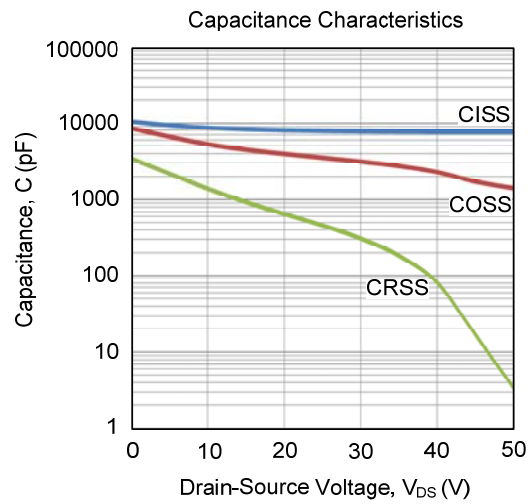
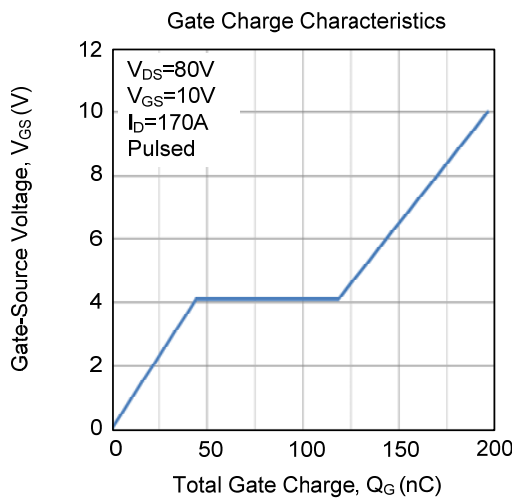
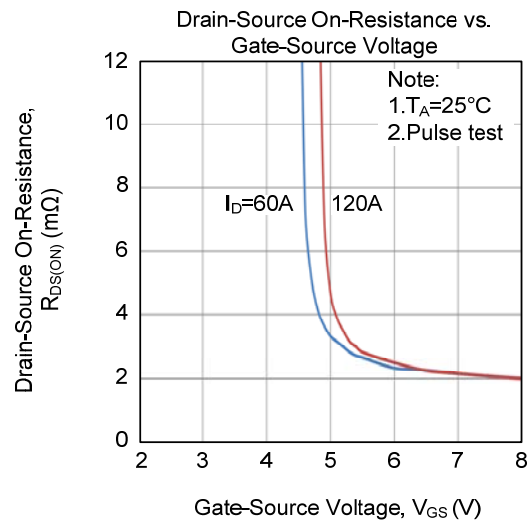
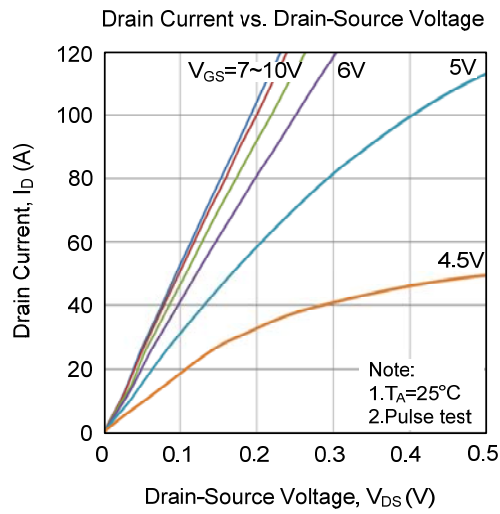


Unclamped Inductive Switching Test Circuit

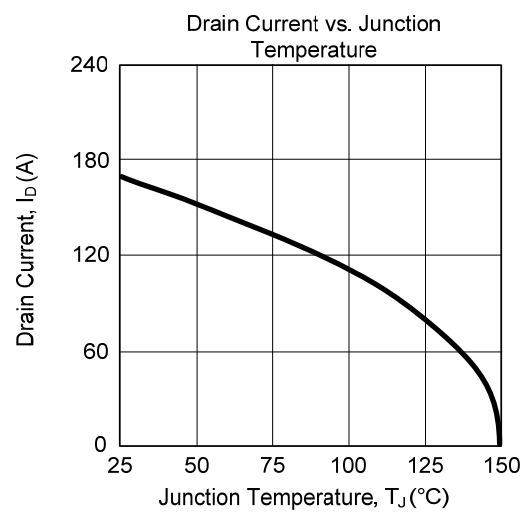
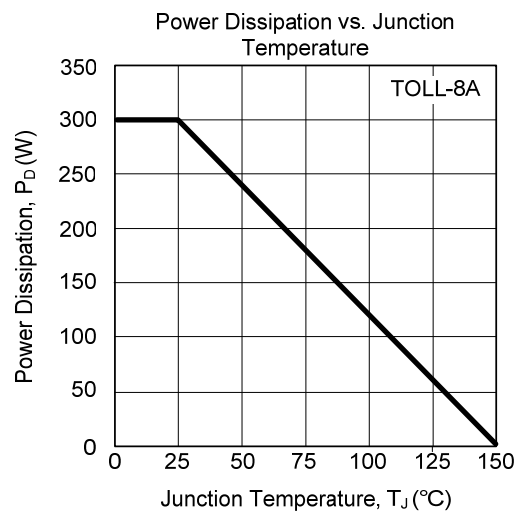
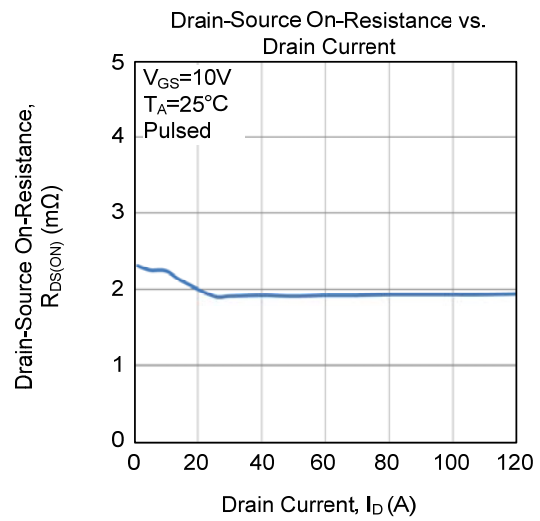
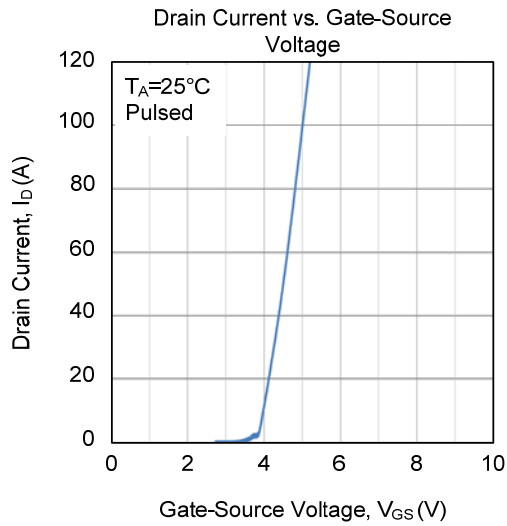
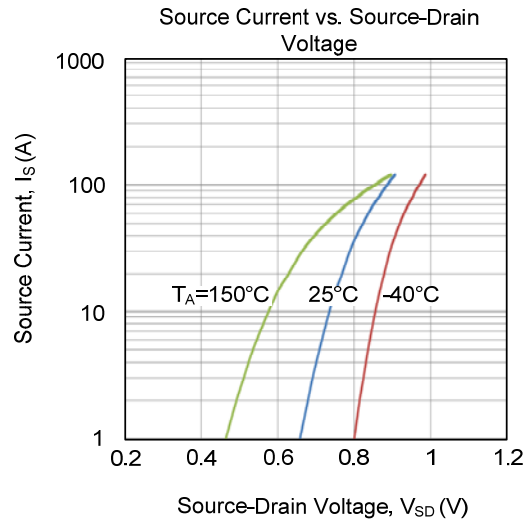
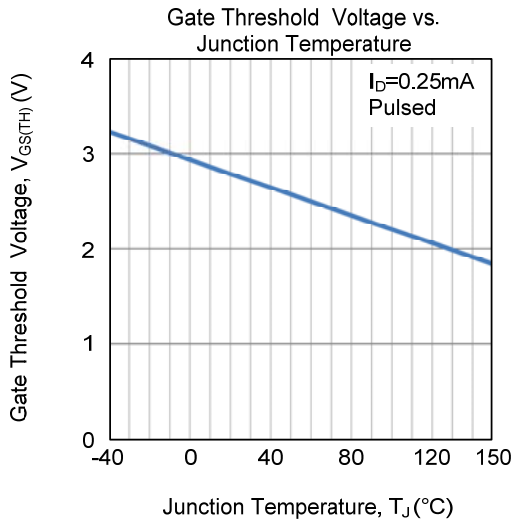


Unclamped Inductive Switching Waveforms

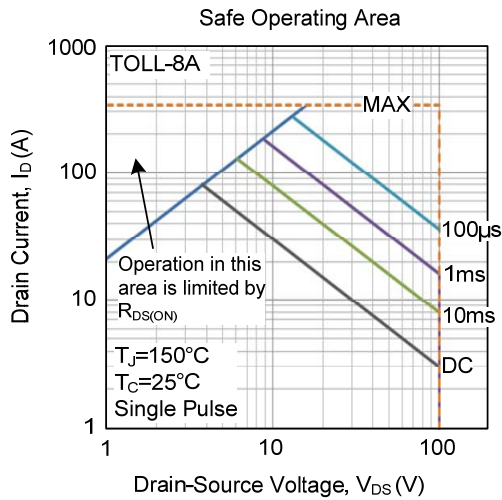
TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



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